

**Search Notes**

Application/Control No.

10/786,164

Examiner

Alvin C. Chin-Shue

Applicant(s)/Patent under  
Reexamination

BEAN ET AL.

Art Unit

3634

**SEARCHED**

Class	Subclass	Date	Examiner
182	2.1 →	6.20.05	AS
	2.11		
	63.1		
	69.6		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR